

^{134}Xe IT decay (5 μs) 2001Ge07

Type	Author	History Citation	Literature Cutoff Date
Full Evaluation	A. A. Sonzogni	NDS 103, 1 (2004)	31-Jul-2004

Parent: ^{134}Xe : E=3025.2 15; $J^\pi=(10^+)$; $T_{1/2}=5 \mu\text{s}$ 1; %IT decay=100.0

Source produced with $^{239}\text{Pu}(\text{n},\text{F})$ and $^{241}\text{Pu}(\text{n},\text{F})$ E=thermal. Measured E_γ , ce γ -electron coincidence following fission fragment separation using LOHENGRIN. Two Ge and 2 Si(Li) detectors.

 ^{134}Xe Levels

E(level) [†]	J^π [‡]	$T_{1/2}$	Comments
0.0	0 ⁺		
847.0 3	2 ⁺		
1731.3 5	4 ⁺		
2136.7 6	6 ⁺		
2997.3 6	(8 ⁺)		
3025.3 12	(10 ⁺)	5 μs 1	$T_{1/2}$: from 861 $\gamma(\text{t})$.

[†] From least-squares fit to E_γ assuming $\Delta E_\gamma=0.3 \text{ keV}$ when unknown.

[‡] From Adopted Levels.

 $\gamma(^{134}\text{Xe})$

E_γ	$E_i(\text{level})$	J^π_i	E_f	J^π_f	Mult.	Comments
28 1	3025.3	(10 ⁺)	2997.3	(8 ⁺)	E2	Mult.: from RUL. E_γ : deduced from 23 keV 1 electron conversion line.
405.4	2136.7	6 ⁺	1731.3	4 ⁺		
847.0	847.0	2 ⁺	0.0	0 ⁺		
860.6	2997.3	(8 ⁺)	2136.7	6 ⁺		
884.3	1731.3	4 ⁺	847.0	2 ⁺		

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%IT=100.0

